

Final Assessment Test - April 2019

- Semiconductor Devices and Circults Course ECE1002

Class NBR(s): 1225 / 1227 / 1231 / 1233 / 1235 / 1239/

Time: Three Hours

Max. Marks: 100

Slot: C1+TC1

General Instruction: Important constants: k=1.38=10" J/K, h=6.625=10" J-s, mu=9.11=10" kg, c=8.85=10" F/cm. $q = 1.6 \times 10^{-19}$ C, For Si: $E_e = 1.12$ eV, m (300 K) = 10^{10} /cm², $e_i = 11.7$ E.

> Answer ALL Questions (10 x 10 = 100 Marks)

- I) A thin film of silicon layer was grown using chemical vapour deposition, it was found that the doping concentrations $N_A = 5 \times 10^{17}$ cm 4 and $N_D = 3 \times 10^{13}$ cm 4 at 300 K. Find the following:
 - t. Type of semiconductor
 - Position of Femi-level from valance band at equilibrium. II.
 - Minority carrier concentration
 - II) A Si bar was doped with boron at 1013 cm⁻². A short pulse of light was exposed and found the electron-hole pair generation rate as 10 2/s cm2 and recombination lifetime as 10 µs. Determine the following:
 - Majority and minority carrier concentrations
 - Excess charge carriers produced after illumination of light

[OR]

- b) in a 5.4 mm long n-type silicon har with rectangular cross section 50 μm ×100 μm, the measured drift current at 300 K was 2.8 µA. It was found that the electron mobility is 1500 cm²/V-s for the donor concentration is 5×10^{14} /cm². Assume $\mu_p=450$ cm²/Vs. Calculate:
 - Electron and hole concentrations
 - Resistivity of the sample.
 - iii. Average electric field across the sample

Applied voltage across the sample.

A p-n junction has a built-in potential of 0.65V and the donor concentration on the N-side is 5 times the acceptor concentration on the P-side. If the intripsic carrier concentration is 1011 cm 3 at 100°C, find the doping concentration on the P-side, width of the depletion region and the distance it extends in the P-side and in the N-side of the junction. Also, find the value of the depletion capacitance when a reverse bias of 2 V is applied across it for a cross sectional area of 0.5 cm². Assume the relative dielectric constant is 10.

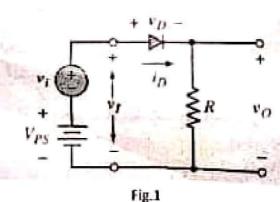
of With the help of band diagrams explain the operation and V-I characteristics of tunnel diodes.

Explain the differences between Avalanche and Zener breakdown mechanisms.

Analyze the circuit (by determining $V_0 \otimes v_n$). Assume circuit and diode parameters of $V_{0s} = 5 \text{ V}$, $R = 5 \text{ k}\Omega$, $V_{\nu} = 0.6 \text{ V & } v_{\nu} = 0.1 \sin \omega t$



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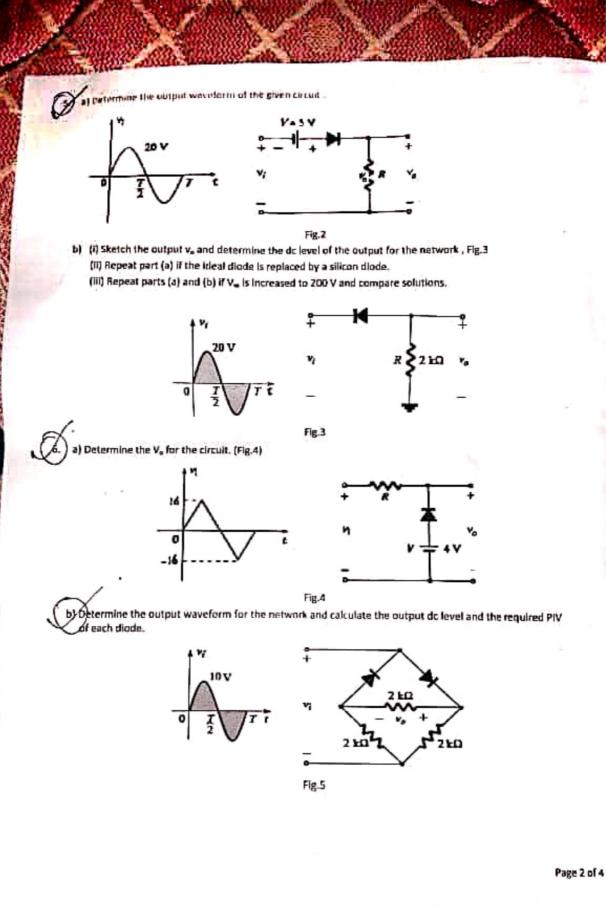


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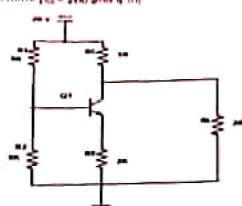
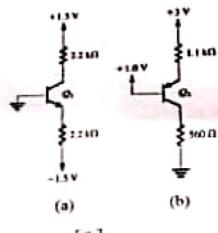


Fig.6

Find the values of voltages at emitter, collector and base terminal and the current flowing through each terminal. Use $\beta = 30$ and $V_{ee} = 0.7V$.



Fut. 7

 a) i) Calculate the total charge in the channel of NMOS Transistor which has: 9.

$$C_{ox} = 9 \frac{fF}{\mu m^2}$$
; $L = 0.36 \ \mu m$; $W = 3.6 \ \mu m$; $V_{ay} = 0.2 \ V$ and $V_{DS} = 0 \ V$.

ii) Refer to the Fig. 8 the MOSFET hat $V_t=0.7\,V$; $\mu_nC_{\rm ex}=100\,\mu A/V^2$; $L=1\,\mu m$ and $W=32\,\mu m$. Design the circuit to have a drain current of 0.4 mA with

 $V_0 = 0.5 \text{ V}$, calculate the values of R_3 and R_0 .

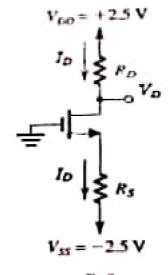


Fig.8

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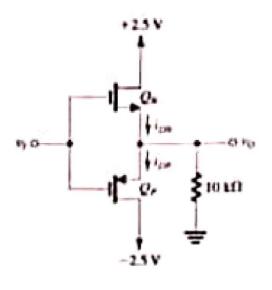
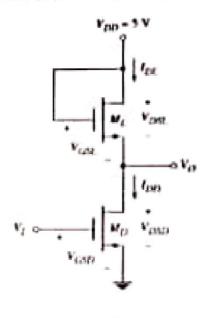


Fig.9

10. Determine the dr transistor contents and voltages in a circuit 9 Fig.t0 containing an enhancement load device. The transistors in the circuit (shown in Figure) have parameters VTNO × VTNL × IV, E_m × 50 μA/V², and E_m × 10 μA/V. Also assume A_m × A_m × 0. (The subscript D applies to the driver transistor and the subscript L applies to the load transistor.) Determine V_m for V_m × SV and V_m × 1.5V.



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Fig. 10